

<b>Notice of References Cited</b>	Application/Control No. 10/827,012	Applicant(s)/Patent Under Reexamination DIERKS, DIETER	
	Examiner Henok G. Heyi	Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,297,436 A	10-1981	Kubotera et al.	430/319
*	B	US-4,588,664 A	05-1986	Fielding et al.	430/1
*	C	US-5,244,774 A	09-1993	Usami et al.	430/270.14
*	D	US-5,667,953 A	09-1997	Bertoldi et al.	430/567
*	E	US-6,066,218 A	05-2000	Kuhn et al.	156/87
*	F	US-6,205,112 B1	03-2001	Weidner, Steven Lee	369/275.3
*	G	US-6,235,461 B1	05-2001	Sismondi et al.	430/569
*	H	US-2003/0099911 A1	05-2003	Ceruti et al.	430/621
*	I	US-6,747,930 B1	06-2004	Weldon et al.	369/53.21
*	J	US-2006/0250930 A1	11-2006	Worthington et al.	369/100
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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